

10/553725

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PATENT
ATTORNEY DOCKET NO. 0074/057001

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

#2

Applicants: Takuji MAEDA et al. Art Unit:
Application No.: filed concurrently Examiner:
Title: SEMICONDUCTOR MEMORY CARD, SEMICONDUCTOR MEMORY CONTROL
APPARATUS, AND SEMICONDUCTOR MEMORY CONTROL METHOD
International Application No.: PCT/JP2004/013703
International Filing Date : September 13, 2004
Priority Date : September 18, 2003
U.S. Filing Date : October 19, 2005

Mail Stop PCT

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

INFORMATION DISCLOSURE STATEMENT

Sir:

Pursuant to their duty of good faith and candor as set forth in 37 CFR 1.56(a), applicants request that the references cited on attached form PTO-1449 (a copy of which is enclosed) be considered by the Examiner in connection with the search of the prior art required by 37 CFR 1.104.

Enclosed also please find a copy of the International Search Report citing these references. The relevance of these references can be seen from the International Search Report. The English abstracts for the Japanese references are also enclosed.

Please note that the enclosed Japanese Patent Application Publication No. 11-191297 is discussed on page 2 of the specification.

Please also note that enclosed are copies of U.S. Patent No. 6,725,322, U.S. Patent Application Publication Nos. 2004-30825 and 2004-193774 which are the English language counterparts for International Application Publication No. WO 2000/50997, Japanese Patent Application Publication Nos. 2002-202912 and 2003-044351, respectively.

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Information Disclosure Statement

Applicants: Takuji MAEDA et al.

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Please note that the English language translations of three Japanese Patent Application Publications are also enclosed. Please also note that these English translations are machine translations provided by the Japan Patent Office and the Japan Patent Office states that the translations may not precisely reflect the original Japanese text.

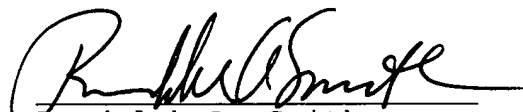
This Statement is being filed under 37 CFR 1.97(b) prior to the mailing date of a first Office Action on the merits.

It is respectfully requested that the above information be considered by the Examiner and that a copy of the enclosed Form PTO-1449 be returned indicating that such information has been considered.

Applicants' undersigned attorney may be reached at the telephone number listed below. All correspondence should continue to be directed to our address below.

Respectfully submitted,

Date: October 19, 2005


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Substitute for form 1449A/PTO

Complete if Known

INFORMATION DISCLOSURE
STATEMENT BY APPLICANT

(use as many sheets as necessary)

Sheet 1 of 1

Application Number	Filed on 10/18/2005
Filing Date	October 19, 2005
Applicants	Takuji MAEDA et al.
Group Art Unit	
Examiner Name	
Attorney Docket Number	0074/057001

U.S. PATENT DOCUMENTS

EXAMINER INITIAL*	Cite No. ¹	DOCUMENT NUMBER Kind Code ² (if known)		NAME	DATE MM-YYYY	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
		2004-30825	A	OTAKE et al.	02/2004	
		6,725,322	B	SHIRAISHI et al.	04/2004	
		2004-193774	A	IWATA et al.	09/2004	

FOREIGN PATENT DOCUMENTS

EXAMINER INITIAL*	Cite No. ¹	Foreign Patent Document			NAME	DATE MM-YYYY	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear	T ⁶
		Kind Code ⁵ Office ³ (if known)	Number ⁴					
		JP	6-124175	A	FUKUMOTO	05/1994		X
		JP	11-191297	A	KATAYAMA et al.	07/1999		X
		WO	00/50997	A	SHIRAISHI et al.	08/2000		
		JP	2002-202912	A	OTAKE et al.	07/2002		Abstract
		JP	2003-044351	A	IWATA et al.	02/2003		Abstract
		JP	2003-058417	A	SHIYOURAIDEN et al.	02/2003		X

EXAMINER

DATE CONSIDERED

*Examiner: Initial if citation considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

¹Unique citation designation number. ²Applicant is to place a check mark here if English language Translation is attached. ³Enter Office that issued the document, by the two-letter code (WIPO Standard ST.3). ⁴For Japanese patent documents, the indication of the year of the reign of the Emperor must precede the serial number of the patent document. ⁵Kind of document by the appropriate symbols as indicated on the document under WIPO Standard ST. 16 if possible. ⁶Applicant is to place a check mark here if English language Translation is attached.